MOSFET – Dual, N-Channel, POWERTRENCH®

Q1: 40 V, 156 A, 1.5 m Ω Q2: 40 V, 156 A, 1.5 m Ω

FDMD8540L

General Description

This device includes two 40 V N-Channel MOSFETs in a dual Power (5 mm x 6 mm) package. HS source and LS drain internally connected for half/full bridge, low source inductance package, low $r_{DS(on)}/Qg$ FOM silicon.

Features

Q1: N-Channel

- Max $r_{DS(on)} = 1.5 \text{ m}\Omega$ at $V_{GS} = 10 \text{ V}$, $I_D = 33 \text{ A}$
- Max $r_{DS(on)}$ = 2.2 m Ω at V_{GS} = 4.5 V, I_D = 26 A Q2: N-Channel
- Max $r_{DS(on)} = 1.5 \text{ m}\Omega$ at $V_{GS} = 10 \text{ V}$, $I_D = 33 \text{ A}$
- Max $r_{DS(on)} = 2.2 \text{ m}\Omega$ at $V_{GS} = 4.5 \text{ V}$, $I_D = 26 \text{ A}$
- Ideal for Flexible Layout in Primary Side of Bridge Topology
- 100% UIL Tested
- Kelvin High Side MOSFET Drive Pin-out Capability
- This Device is Pb-Free and are RoHS Compliant

Applications

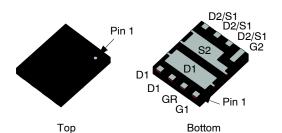
- POL Synchronous Dual
- One Phase Motor Half Bridge
- Half/Full Bridge Secondary Synchronous Rectification



ON Semiconductor®

www.onsemi.com

V _{DS}	r _{DS(ON)} MAX	I _D MAX
40 V	1.5 mΩ @ 10 V	156 A
	2.2 mΩ @ 4.5 V	

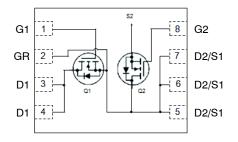


PQFN8 5X6, 1.27P Power 5 x 6 CASE 483AT

MARKING DIAGRAM

\$Y&Z&3&K FDMD 8540L

FDMD8540L = Specific Device Code \$Y = ON Semiconductor Logo &Z = Assembly Plant Code &3 = 3-Digit Date Code Format &K = 2-Digits Lot Run Traceability Data



ORDERING INFORMATION

See detailed ordering and shipping information on page 9 of this data sheet.

MOSFET MAXIMUM RATINGS (T_A = 25°C unless otherwise noted)

Symbol		Parameter				Unit
V _{DS}	Drain to Source Voltage			40	40	V
V _{GS}	Gate to Source Voltage			±20	±20	V
I _D	Drain Current	- Continuous	T _C = 25°C (Note 3)	156	156	Α
		- Continuous	T _C = 100°C (Note 3)	99	99	
		- Continuous	T _A = 25°C	33 (Note 4a)	33 (Note 4b)	
		- Pulsed	(Note 2)	886	886	1
E _{AS}	Single Pulse Avalanche Energy (Note 1)		541	541	mJ	
P _D	Power Dissipation T _C = 25		T _C = 25°C	62	62	W
	Power Dissipation		T _A = 25°C	2.3 (Note 4a)	2.3 (Note 4b)	1
T _J , T _{STG}	Operating and Storag	ge Junction Temperature Ra	ange	–55 to	+150	°C

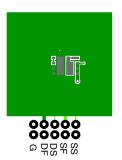
Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

- 1. Q1: E_{AS} of 541 mJ is based on starting T_J = 25°C, L = 3 mH, I_{AS} = 19 A, V_{DD} = 40 V, V_{GS} = 10 V. 100% tested at L = 0.1 mH, I_{AS} = 59 A. Q2: E_{AS} of 541 mJ is based on starting T_J = 25°C, L = 3 mH, I_{AS} = 19 A, V_{DD} = 40 V, V_{GS} = 10 V. 100% tested at L = 0.1 mH, I_{AS} = 59 A. 2. Pulsed Id please refer to Figure 11 and Figure 24 SOA graph for more details.
- 3. Computed continuous current limited to Max Junction Temperature only, actual continuous current will be limited by thermal & electro-mechanical application board design.

THERMAL CHARACTERISTICS

Symbol	Parameter	Q1	Q2	Unit
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case		2.0	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	55 (Note 4a)	55 (Note 4b)	

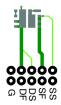
R_{0,JA} is determined with the device mounted on a 1 in² pad 2 oz copper pad on a 1.5 x 1.5 in. board of FR-4 material. R_{0,JC} is guaranteed by design while $R_{\theta CA}$ is determined by the user's board design.



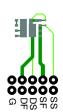
a. 55°C/W when mounted on a 1 in² pad of 2 oz copper



b. 55°C/W when mounted on a 1 in² pad of 2 oz copper



c. 155°C/W when mounted on a minimum pad of 2 oz copper



d. 155°C/W when mounted on a minimum pad of 2 oz copper

ELECTRICAL CHARACTERISTICS (T_{.I} = 25°C unless otherwise noted)

Symbol	Parameter	Test Condi	tion	Type	Min	Тур	Max	Unit
	RACTERISTICS	1				,,,		
BV _{DSS}	Drain to Source Breakdown Voltage	I _D = 250 μA, V _{GS} = 0	V	Q1	40	T _	_	V
D • DSS	Brain to ocaree Breakdown Volkage	10 - 200 μπ, νας - σ	•	Q2	40	-	-	
ΔBV_{DSS}	Breakdown Voltage Temperature	I _D = 250 mA, referenced to 25°C		Q1	-	20	_	mV/°C
ΔT_{J}	Coefficient			Q2	-	20	_	
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 32 V, V _{GS} = 0 V		Q1	-	-	1	μΑ
		\ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \		Q2	_	-	1	
I _{GSS}	Gate to Source Leakage Current	$V_{GS} = \pm 20 \text{ V}, V_{DS} = 0$	V	Q1 Q2	_	_	±100 ±100	nA
ON CHAR	ACTERISTICS						ı	I.
V _{GS(th)}	Gate to Source Threshold Voltage	V _{GS} = V _{DS} , I _D = 250 mA		Q1	1.0	1.8	3.0	V
				Q2	1.0	1.8	3.0	
$\frac{\Delta V_{GS(th)}}{}$	Gate to Source Threshold Voltage Temperature Coefficient	$I_D = 250 \mu A$, reference	ed to 25°C	Q1 Q2	_	-6 -6	_	mV/°C
$\Delta T_{ m J}$,							
r _{DS(on)}	Static Drain to Source On Resistance	V _{GS} = 10 V, I _D = 33 A		Q1	_	1.25	1.5	mΩ
		$V_{GS} = 4.5 \text{ V}, I_D = 26 \text{ A}$			-	1.65	2.2	
		V _{GS} = 10 V, I _D = 33 A			-	1.7	2.1	
		$V_{GS} = 10 \text{ V}, I_D = 33 \text{ A}$		Q2	-	1.25	1.5	
		$V_{GS} = 4.5 \text{ V}, I_D = 26 \text{ A}$			-	1.65	2.2	
		$V_{GS} = 10 \text{ V}, I_D = 33 \text{ A}$, T _J = 125°C		_	1.7	2.1	
9 _{FS}	Forward Transconductance	$V_{DD} = 5 \text{ V}, I_{D} = 33 \text{ A}$		Q1 Q2	-	178 178	-	S
DYNAMIC	CHARACTERISTICS							
	<u> </u>	V _{DS} = 20 V, V _{GS} = 0 \	/	Q1	_	5670	7940	pF
C _{iss}	Input Capacitance	V _{DS} = 20 V, V _{GS} = 0 \ f = 1 MHz	/	Q1 Q2	- -	5670 5670	7940 7940	pF
	<u> </u>	V _{DS} = 20 V, V _{GS} = 0 \ f = 1 MHz	/	Q2 Q1	-	5670 1668	7940 2335	pF pF
C _{iss}	Input Capacitance Output Capacitance	V _{DS} = 20 V, V _{GS} = 0 \ f = 1 MHz	/	Q2 Q1 Q2	- - -	5670 1668 1668	7940 2335 2335	pF
C _{iss}	Input Capacitance	V _{DS} = 20 V, V _{GS} = 0 \ f = 1 MHz	/	Q2 Q1	-	5670 1668	7940 2335	
C _{iss}	Input Capacitance Output Capacitance	V _{DS} = 20 V, V _{GS} = 0 \ f = 1 MHz	/	Q2 Q1 Q2 Q1 Q2 Q1	- - - - - 0.1	5670 1668 1668 75 75 75	7940 2335 2335 135 135 3.2	pF
C _{iss} C _{oss} C _{rss}	Input Capacitance Output Capacitance Reverse Transfer Capacitance Gate Resistance	V _{DS} = 20 V, V _{GS} = 0 V f = 1 MHz	/	Q2 Q1 Q2 Q1 Q2	- - -	5670 1668 1668 75 75	7940 2335 2335 135 135	pF pF
C _{iss} C _{oss} C _{rss} R _g	Input Capacitance Output Capacitance Reverse Transfer Capacitance Gate Resistance	f = 1 MHz		Q2 Q1 Q2 Q1 Q2 Q1 Q2	- - - - - 0.1	5670 1668 1668 75 75 75	7940 2335 2335 135 135 3.2	pF pF
C _{iss} C _{oss} C _{rss}	Input Capacitance Output Capacitance Reverse Transfer Capacitance Gate Resistance	f = 1 MHz		Q2 Q1 Q2 Q1 Q2 Q1	- - - - - 0.1	5670 1668 1668 75 75 75	7940 2335 2335 135 135 3.2	pF pF
C_{iss} C_{oss} C_{rss} R_g SWITCHIN $t_{d(on)}$	Input Capacitance Output Capacitance Reverse Transfer Capacitance Gate Resistance IG CHARACTERISTICS Turn-On Delay Time	f = 1 MHz		Q2 Q1 Q2 Q1 Q2 Q1 Q2 Q1 Q2	- - - - 0.1 0.1	5670 1668 1668 75 75 1.6 1.6	7940 2335 2335 135 135 3.2 3.2	pF pF Ω
C _{iss} C _{oss} C _{rss} R _g	Input Capacitance Output Capacitance Reverse Transfer Capacitance Gate Resistance	f = 1 MHz		Q2 Q1 Q2 Q1 Q2 Q1 Q2	- - - - 0.1 0.1	5670 1668 1668 75 75 1.6 1.6	7940 2335 2335 135 135 3.2 3.2	pF pF Ω
C_{iss} C_{oss} C_{rss} R_g SWITCHIN $t_{d(on)}$	Input Capacitance Output Capacitance Reverse Transfer Capacitance Gate Resistance IG CHARACTERISTICS Turn-On Delay Time	f = 1 MHz		Q2 Q1 Q2 Q1 Q2 Q1 Q2 Q1 Q2 Q1 Q2	- - - - 0.1 0.1	5670 1668 1668 75 75 1.6 1.6 15 15 13 13	7940 2335 2335 135 135 3.2 3.2 28 28 24 24 81	pF pF Ω
C_{iss} C_{oss} C_{rss} R_g SWITCHIN $t_{d(on)}$ t_r $t_{d(off)}$	Input Capacitance Output Capacitance Reverse Transfer Capacitance Gate Resistance IG CHARACTERISTICS Turn-On Delay Time Rise Time Turn-Off Delay Time	f = 1 MHz		Q2 Q1 Q2 Q1 Q2 Q1 Q2 Q1 Q2 Q1 Q2	- - - - 0.1 0.1	5670 1668 1668 75 75 1.6 1.6 15 15 13 13 51 51	7940 2335 2335 135 135 3.2 3.2 28 28 24 24 81 81	pF pF Ω ns ns
C_{iss} C_{oss} C_{rss} R_g SWITCHIN $t_{d(on)}$	Input Capacitance Output Capacitance Reverse Transfer Capacitance Gate Resistance IG CHARACTERISTICS Turn-On Delay Time Rise Time	f = 1 MHz		Q2 Q1 Q2 Q1 Q2 Q1 Q2 Q1 Q2 Q1 Q2	- - - - 0.1 0.1	5670 1668 1668 75 75 1.6 1.6 15 15 13 13	7940 2335 2335 135 135 3.2 3.2 28 28 24 24 81	pF pF Ω ns
C_{iss} C_{oss} C_{rss} R_g SWITCHIN $t_{d(on)}$ t_r $t_{d(off)}$	Input Capacitance Output Capacitance Reverse Transfer Capacitance Gate Resistance IG CHARACTERISTICS Turn-On Delay Time Rise Time Turn-Off Delay Time	f = 1 MHz	Ω V _{DD} = 20 V,	Q2 Q1	- - - 0.1 0.1	5670 1668 1668 75 75 1.6 1.6 15 13 13 13 51 51 14 14 81	7940 2335 2335 135 135 3.2 3.2 28 28 24 24 81 81 25 25 113	pF pF Ω ns ns
C_{iss} C_{oss} C_{rss} R_{g} $SWITCHIN$ $t_{d(on)}$ t_{r} $t_{d(off)}$ t_{f} $Q_{g(TOT)}$	Input Capacitance Output Capacitance Reverse Transfer Capacitance Gate Resistance IG CHARACTERISTICS Turn-On Delay Time Rise Time Turn-Off Delay Time Fall Time Total Gate Charge	V _{DD} = 20 V, I _D = 33 A V _{GS} = 10 V, R _{GEN} = 6	V _{DD} = 20 V, I _D = 33 A	Q2 Q1 Q2	- - - - 0.1 0.1	5670 1668 1668 75 75 1.6 1.6 15 13 13 13 51 51 14 14 81 81	7940 2335 2335 135 135 135 3.2 3.2 28 28 24 24 24 81 81 25 25 113 113	pF pF Ω ns ns ns nc
C_{iss} C_{oss} C_{rss} R_{g} $SWITCHIN$ $t_{d(on)}$ t_{r} $t_{d(off)}$ t_{f}	Input Capacitance Output Capacitance Reverse Transfer Capacitance Gate Resistance IG CHARACTERISTICS Turn-On Delay Time Rise Time Turn-Off Delay Time Fall Time	V _{DD} = 20 V, I _D = 33 A V _{GS} = 10 V, R _{GEN} = 6	Ω V _{DD} = 20 V,	Q2 Q1	- - - 0.1 0.1	5670 1668 1668 75 75 1.6 1.6 15 13 13 13 51 51 14 14 81	7940 2335 2335 135 135 3.2 3.2 28 28 24 24 81 81 25 25 113	pF pF Ω ns ns
C_{iss} C_{oss} C_{rss} R_{g} $SWITCHIN$ $t_{d(on)}$ t_{r} $t_{d(off)}$ t_{f} $Q_{g(TOT)}$	Input Capacitance Output Capacitance Reverse Transfer Capacitance Gate Resistance IG CHARACTERISTICS Turn-On Delay Time Rise Time Turn-Off Delay Time Fall Time Total Gate Charge	V _{DD} = 20 V, I _D = 33 A V _{GS} = 10 V, R _{GEN} = 6	V _{DD} = 20 V, I _D = 33 A V _{DD} = 20 V, I _D = 33 A	Q2 Q1	- - - 0.1 0.1	5670 1668 1668 75 75 1.6 1.6 15 13 13 51 51 14 14 81 81 81 38 38	7940 2335 2335 135 135 135 3.2 3.2 28 28 24 24 81 81 25 25 113 113	pF pF Ω ns ns ns nc
C_{iss} C_{oss} C_{rss} R_g $SWITCHIN$ $t_{d(on)}$ t_r $t_{d(off)}$ t_f $Q_{g(TOT)}$	Input Capacitance Output Capacitance Reverse Transfer Capacitance Gate Resistance IG CHARACTERISTICS Turn-On Delay Time Rise Time Turn-Off Delay Time Fall Time Total Gate Charge Total Gate Charge	$V_{DD} = 20 \text{ V, } I_{D} = 33 \text{ A}$ $V_{GS} = 10 \text{ V, } R_{GEN} = 6$ $V_{GS} = 0 \text{ V to } 10 \text{ V}$ $V_{GS} = 0 \text{ V to } 4.5 \text{ V}$	V _{DD} = 20 V, I _D = 33 A V _{DD} = 20 V, I _D = 33 A	Q2 Q1 Q2	- - - 0.1 0.1	5670 1668 1668 75 75 1.6 1.6 15 13 13 13 51 51 14 14 81 81 81 38 38	7940 2335 2335 135 135 3.2 3.2 28 28 24 24 81 81 25 25 113 113 54 54	pF pF Ω ns ns ns nc nC

ELECTRICAL CHARACTERISTICS (T_J = 25°C unless otherwise noted) (continued)

Symbol	Parameter	Test Condition	Type	Min	Тур	Max	Unit
DRAIN-SC	OURCE DIODE CHARACTERISTICS						
V_{SD}	Source to Drain Diode Forward Voltage	V _{GS} = 0 V, I _S = 33 A (Note 5)	Q1 Q2	_ _	0.8 0.8	1.3 1.3	V
V_{SD}	Source to Drain Diode Forward Voltage	V _{GS} = 0 V, I _S = 2 A (Note 5)	Q1 Q2	- -	0.7 0.7	1.2 1.2	V
t _{rr}	Reverse Recovery Time	I _F = 33 A, di/dt = 100 A/μs	Q1 Q2	- -	54 54	86 86	ns
Q _{rr}	Reverse Recovery Charge		Q1 Q2	- -	38 38	60 60	nC

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

5. Pulse Test: Pulse Width < 300 µs, Duty cycle < 2.0 %.

TYPICAL CHARACTERISTICS (Q1 N-CHANNEL)

(T_J = 25°C unless otherwise noted)

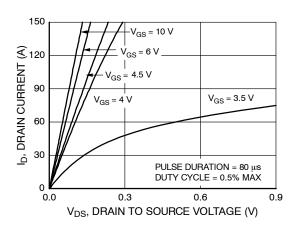


Figure 1. On Region Characteristics

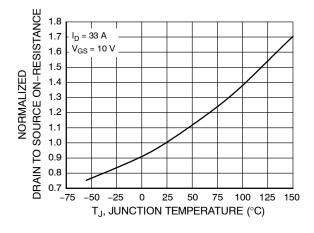


Figure 3. Normalized On Resistance vs. Junction Temperature

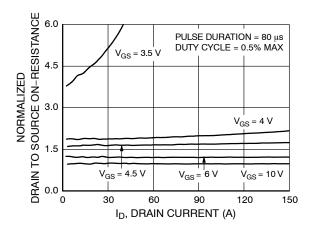


Figure 2. Normalized On–Resistance vs.
Drain Current and Gate Voltage

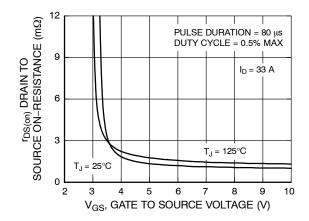


Figure 4. On-Resistance vs. Gate to Source Voltage

TYPICAL CHARACTERISTICS (Q1 N-CHANNEL)

 $(T_J = 25^{\circ}C \text{ unless otherwise noted})$ (continued)

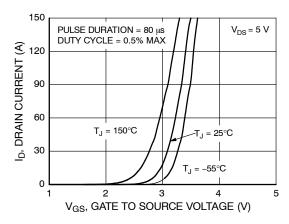


Figure 5. Transfer Characteristics

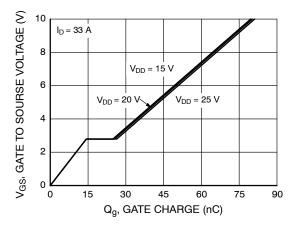


Figure 7. Gate Charge Characteristics

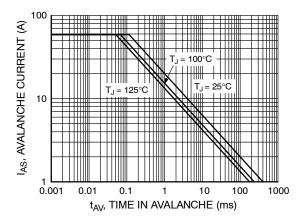


Figure 9. Unclamped Inductive Switching Capability

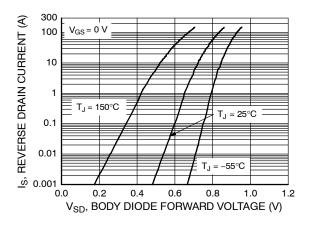


Figure 6. Source to Gate Diode Forward Voltage vs. Source Current

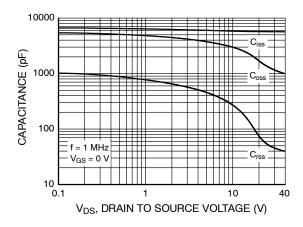


Figure 8. Capacitance vs. Drain to Source Voltage

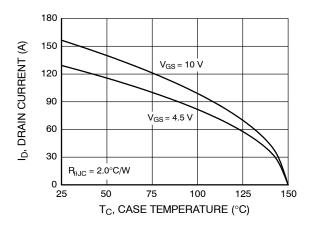


Figure 10. Maximum Continuous Drain Current vs. Case Temperature

TYPICAL CHARACTERISTICS (Q1 N-CHANNEL)

 $(T_J = 25^{\circ}C \text{ unless otherwise noted})$ (continued)

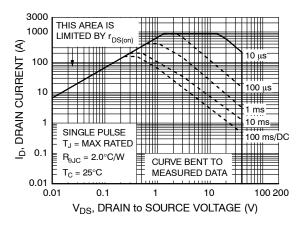


Figure 11. Forward Bias Safe Operating Area

Figure 12. Single Pulse Maximum Power Dissipation

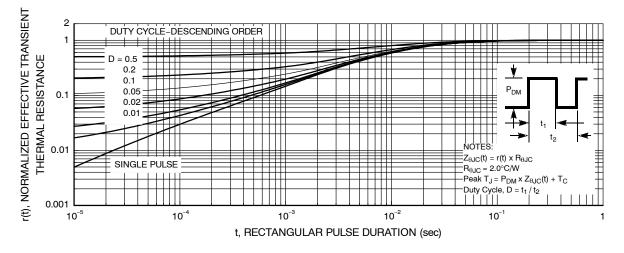


Figure 13. Junction-to-Case Transient Thermal Response Curve

TYPICAL CHARACTERISTICS (Q2 N-CHANNEL)

(T_J = 25°C unless otherwise noted)

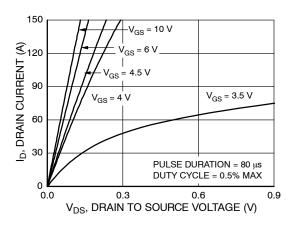


Figure 14. On-Region Characteristics

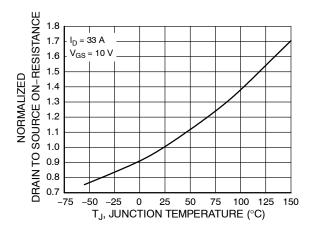


Figure 16. Normalized On Resistance vs. Junction Temperature

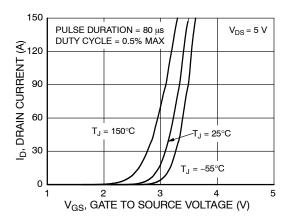


Figure 18. Transfer Characteristics

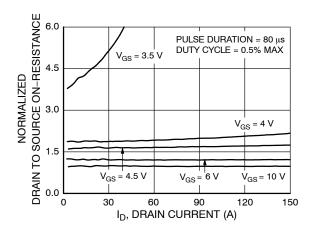


Figure 15. Normalized On-Resistance vs. Drain Current and Gate Voltage

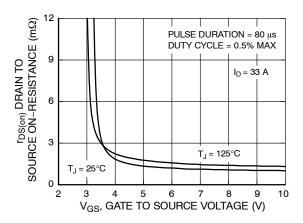


Figure 17. On–Resistance vs. Gate to Source Voltage

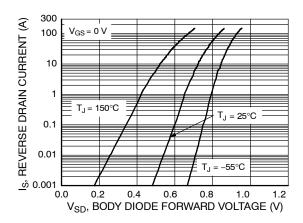


Figure 19. Source to Gate Diode Forward Voltage vs. Source Current

TYPICAL CHARACTERISTICS (Q2 N-CHANNEL)

 $(T_J = 25^{\circ}C \text{ unless otherwise noted})$ (continued)

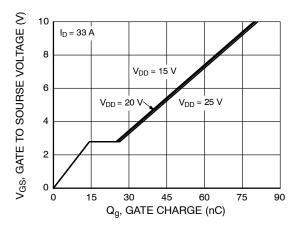


Figure 20. Gate Charge Characteristics

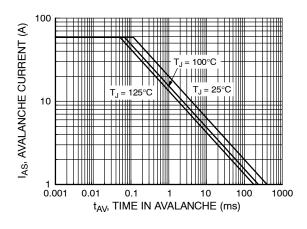


Figure 22. Unclamped Inductive Switching Capability

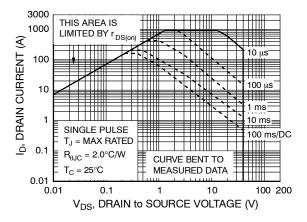


Figure 24. Forward Bias Safe Operating Area

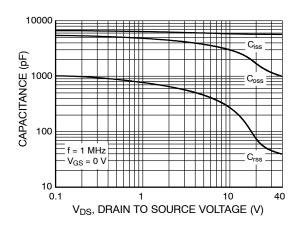


Figure 21. Capacitance vs. Drain to Source Voltage

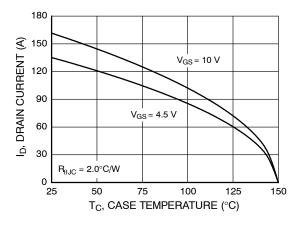


Figure 23. Maximum Continuous Drain Current vs. Case Temperature

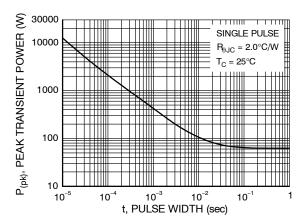


Figure 25. Single Pulse Maximum Power Dissipation

TYPICAL CHARACTERISTICS (Q2 N-CHANNEL)

 $(T_J = 25^{\circ}C \text{ unless otherwise noted})$ (continued)

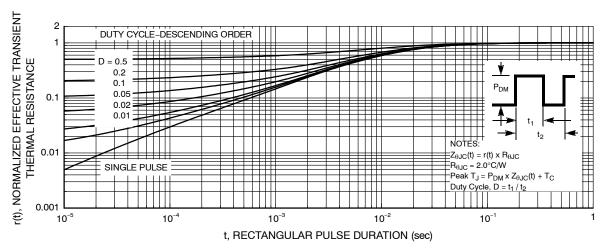


Figure 26. Junction-to-Case Transient Thermal Response Curve

PACKAGE MARKING AND ORDERING INFORMATION

Device Marking	Device	Package Type	Reel Size	Tape Width	Shipping [†]
FDMD8540L	FDMD8540L	PQFN8 5X6, 1.27P Power 5 x 6 (Pb-Free)	13"	12 mm	3000 / Tape & Reel

[†]For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

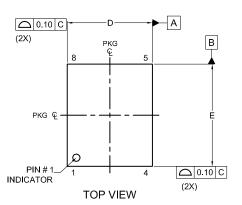
POWERTRENCH is registered trademark of Semiconductor Components Industries, LLC (SCILLC) or its subsidiaries in the United States and/or other countries.

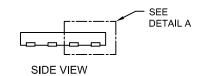


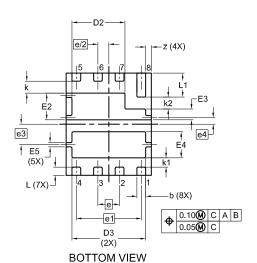
PQFN8 5X6, 1.27P CASE 483AT ISSUE A

// 0.10 C

(8X) 0.08 C **DATE 12 MAR 2021**







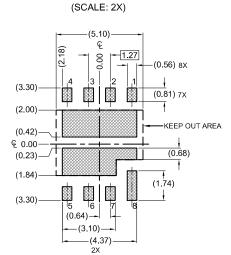
NOTES:

С

SEATING PLANE

A1-

- DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 2009.
- 2. CONTROLLING DIMENSION: MILLIMETERS
- 3. COPLANARITY APPLIES TO THE EXPOSED PADS AS WELL AS THE TERMINALS.
- 4. DIMENSIONS D1 AND E1 DO NOT INCLUDE MOLD FLASH, PROTRUSIONS, OR GATE BURRS.
- 5. SEATING PLANE IS DEFINED BY THE TERMINALS. "A1" IS DEFINED AS THE DISTANCE FROM THE SEATING PLANE TO THE LOWEST POINT ON THE PACKAGE BODY.
- 6. IT IS RECOMMENDED TO HAVE NO TRACES OR VIAS WITHIN THE KEEP OUT AREA.



DETAIL 'A'

LAND PATTERN
RECOMMENDATION

*FOR ADDITIONAL INFORMATION ON OUR PB-FREE STRATEGY AND SOLDERING DETAILS, PLEASE DOWNLOAD THE ON SEMICONDUCTOR SOLDERING AND MOUNTING TECHNIQUES REFERENCE MANUAL, SOLDERRM/D.

MILLIMETERS				
MIN.	NOM.	MAX.		
0.70	0.75	0.80		
0.00		0.05		
0.41	0.51	0.61		
0.10	0.20	0.30		
4.90	5.00	5.10		
3.01	3.11	3.21		
4.22	4.32	4.42		
5.90	6.00	6.10		
1.47	1.57	1.67		
0.53	0.63	0.73		
1.42	1.52	1.62		
0.20	0.25	0.30		
,	1.27 BSC	;		
;	3.81 BSC	;		
(0.64 BSC	;		
-	1.08 BSC	;		
().25 BSC	;		
0.60	0.70	0.80		
0.45	0.55	0.65		
0.60	0.70	0.80		
0.38	0.48	0.58		
1.31	1.41	1.51		
(0.34 REF			
	MIN. 0.70 0.00 0.41 0.10 4.90 3.01 4.22 5.90 1.47 0.53 1.42 0.20 (0.60 0.45 0.60 0.38 1.31	MIN. NOM. 0.70 0.75 0.00 - 0.41 0.51 0.10 0.20 4.90 5.00 3.01 3.11 4.22 4.32 5.90 6.00 1.47 1.57 0.53 0.63 1.42 1.52 0.20 0.25 1.27 BSC 3.81 BSC 0.64 BSC 0.25 BSC 0.60 0.70 0.45 0.55 0.60 0.70 0.38 0.48		

DOCUMENT NUMBER:	98AON13668G	Electronic versions are uncontrolled except when accessed directly from the Document Reposit Printed versions are uncontrolled except when stamped "CONTROLLED COPY" in red.			
DESCRIPTION:	PQFN8 5X6, 1.27P		PAGE 1 OF 1		

ON Semiconductor and are trademarks of Semiconductor Components Industries, LLC dba ON Semiconductor or its subsidiaries in the United States and/or other countries. ON Semiconductor reserves the right to make changes without further notice to any products herein. ON Semiconductor makes no warranty, representation or guarantee regarding the suitability of its products for any particular purpose, nor does ON Semiconductor assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation special, consequential or incidental damages. ON Semiconductor does not convey any license under its patent rights nor the rights of others.

ON Semiconductor and the are trademarks of Semiconductor Components Industries, LLC dba ON Semiconductor or its subsidiaries in the United States and/or other countries. ON Semiconductor owns the rights to a number of patents, trademarks, copyrights, trade secrets, and other intellectual property. A listing of ON Semiconductor's product/patent coverage may be accessed at www.onsemi.com/site/pdf/Patent-Marking.pdf. ON Semiconductor reserves the right to make changes without further notice to any products herein. ON Semiconductor and see no warranty, representation or guarantee regarding the suitability of its products for any particular purpose, nor does ON Semiconductor assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation special, consequential or incidental damages. Buyer is responsible for its products and applications using ON Semiconductor products, including compliance with all laws, regulations and safety requirements or standards, regardless of any support or applications information provided by ON Semiconductor. "Typical" parameters which may be provided in ON Semiconductor data sheets and/or specifications can and do vary in different applications and actual performance may vary over time. All operating parameters, including "Typicals" must be validated for each customer application by customer's technical experts. ON Semiconductor does not convey any license under its patent rights nor the rights of others. ON Semiconductor products are not designed, intended, or authorized for use as a critical component in life support systems or any FDA Class 3 medical devices or medical devices with a same or similar classification in a foreign jurisdiction or any devices intended for implantation in the human body. Should Buyer purchase or use ON Semiconductor products for any such unintended or unauthorized application, Buyer shall indemnify and

PUBLICATION ORDERING INFORMATION

LITERATURE FULFILLMENT:
Email Requests to: orderlit@onsemi.com

ON Semiconductor Website: www.onsemi.com

TECHNICAL SUPPORT North American Technical Support: Voice Mail: 1 800-282-9855 Toll Free USA/Canada Phone: 011 421 33 790 2910

Europe, Middle East and Africa Technical Support:

Phone: 00421 33 790 2910

For additional information, please contact your local Sales Representative